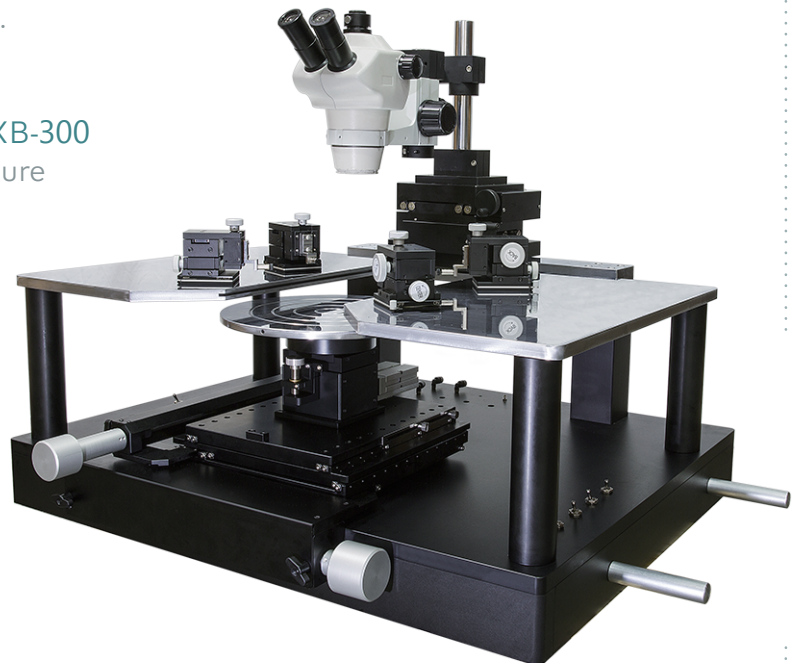


# Model: XB-300

## Analytical Probe Station

» The Probe Station XB-300 is a dedicated probing solution that comes with everything you need to achieve accurate measurement results in the shortest time, with maximum confidence. The system Provides best known methods for I-V/C-V measurements.

Designed for upgradability and extendable with multiple options. The Probe Station XB-300 can be easily reconfigured to meet your future project requirements, such as high voltage testing.



» Accessories

- Microscope Magnification : 1000X
- Hot Chuck : 200/300°C
- Special Chuck Design for RF
- CCD and Screen
- Micropositioner
- Tip Holder
- Shielding Box
- Vibration Free Table
- Platen Up/Down 6mm Adjustable/Coarse Adjustment/Lever-Driven
- Platen Up/Down 25mm Adjustable/Fine Adjustment/Hand wheel-Driven

» Specifications

- Vacuum Chuck 12"
- Huged-Knob Chuck Stage
- Chuck stage 12"×12" Travel
- Chuck Theta 0°~30°
- Chuck Up/Down 4mm Adjustable
- Microscope Stage 2"×2" Travel
- 920mmW x 660mmD x 700mmH With Microscope
- Weight 180kg with microscope

